





Power MOSFETS


DATASHEET

LM30040NAI8A

N-Channel
Enhancement Mode MOSFET

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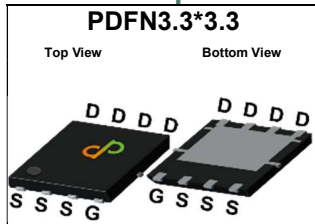


Quality Management Systems

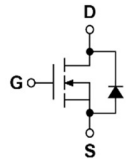
ISO 9001:2015 Certificate

N-Channel Enhancement Mode MOSFET

Pin Description



Symbol



Product Summary

Symbol	N-Channel	Unit
V_{DSS}	30	V
$R_{DS(ON)-Max}$	4	m Ω
I_D	71	A

Feature

- Lower Q_g and Q_{gd} for high-speed switching
- Lower $R_{DS(ON)}$ to Minimize Conduction Losses
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS and R_g Tested

Applications

- Power Management in Notebook Computer, Portable Equipment and Battery Powered Systems

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM30040NAI8A	PDFN3.3*3.3	Tape & Reel	5000 / Tape & Reel	30040 □□□□□□

Note : □□□□□□ = Lot Code

Absolute Maximum Ratings ($T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit
V_{DSS}	Drain-Source Voltage	30	V
V_{GSS}	Gate-Source Voltage	± 20	V
T_J	Maximum Junction Temperature	150	$^\circ\text{C}$
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
I_{DM}	Pulse Drain Current Tested	$T_C=25^\circ\text{C}$ 255	A
I_D	Continuous Drain Current	$T_C=25^\circ\text{C}$ 71 ^①	A
		$T_C=100^\circ\text{C}$ 65	
		$T_C=25^\circ\text{C}$ 42	
P_D	Maximum Power Dissipation	$T_C=100^\circ\text{C}$ 16.7	W
		$T_A=25^\circ\text{C}$ 20	
I_D	Continuous Drain Current	$T_A=70^\circ\text{C}$ 16	A
		$T_A=25^\circ\text{C}$ 1.6	
P_D	Maximum Power Dissipation	$T_A=70^\circ\text{C}$ 1.0	W
		$L=0.1\text{mH}$ 31	
I_{AS} ^②	Avalanche Current, Single pulse	$L=0.5\text{mH}$ 17	A
		$L=0.1\text{mH}$ 48	
E_{AS} ^③	Avalanche Energy, Single pulse	$L=0.5\text{mH}$ 72	mJ

Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State	3 $^\circ\text{C/W}$
$R_{\theta JA}$ ^③	Thermal Resistance-Junction to Ambient	Steady State	80 $^\circ\text{C/W}$

Note ① : Max. current is limited by bonding wire

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C

Note ③ : Surface Mounted on 1in^2 FR-4 board with 1oz.

N-Channel Electrical Characteristics (T_J=25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250uA	30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	V _{DS} =24V, V _{GS} =0V	-	-	1	uA
V_{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250uA	1	1.5	2	V
I_{GSS}	Gate Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
R_{DS(ON)} ^④	Drain-Source On-state Resistance	V _{GS} =10V, I _{DS} =20A	-	3.5	4	mΩ
		V _{GS} =4.5V, I _{DS} =10A	-	4.5	6	
gfs	Forward Transconductance	V _{DS} =5V, I _{DS} =20A	-	28	-	S
Dynamic Characteristics ^⑤						
R_G	Gate Resistance	V _{GS} =0V, V _{DS} =0V, Freq.=1MHz	-	1	-	Ω
C_{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =15V, Freq.=1MHz	-	2435	-	pF
C_{oss}	Output Capacitance		-	308	-	
C_{rss}	Reverse Transfer Capacitance		-	259	-	
td(ON)	Turn-on Delay Time	V _{GS} =10V, V _{DS} =15V, I _D =1A, R _{GEN} =3Ω	-	10.3	-	nS
t_r	Turn-on Rise Time		-	17.6	-	
t_{d(OFF)}	Turn-off Delay Time		-	43.2	-	
t_f	Turn-off Fall Time		-	31.7	-	
Q_g	Total Gate Charge	V _{GS} =4.5V, V _{DS} =15V, I _D =20A	-	33	-	nC
Q_g	Total Gate Charge	V _{GS} =10V, V _{DS} =15V, I _D =20A	-	62	-	
Q_{gs}	Gate-Source Charge		-	10.2	-	
Q_{gd}	Gate-Drain Charge		-	16	-	
Source-Drain Characteristics						
V_{SD} ^④	Diode Forward Voltage	I _{SD} =1A, V _{GS} =0V	-	0.75	1.1	V
t_{rr}	Reverse Recovery Time	I _F =1A, V _R =0V	-	20	-	nS
Q_{rr}	Reverse Recovery Charge	dI _F /dt=100A/μs	-	12	-	nC

Note ④ : Pulse test (pulse width≤300us, duty cycle≤2%).

Note ⑤ : Guaranteed by design, not subject to production testing.

N-Channel Typical Characteristics

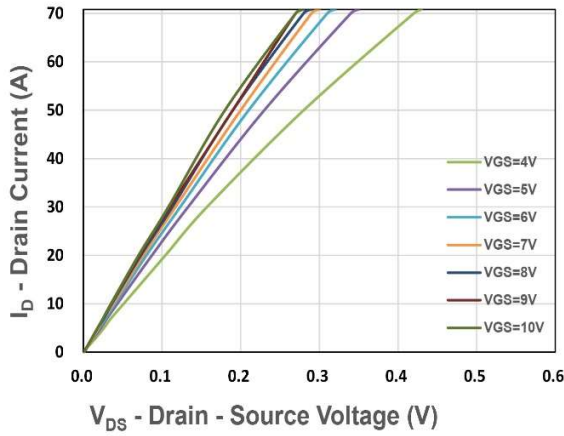


Figure 1. Output Characteristics

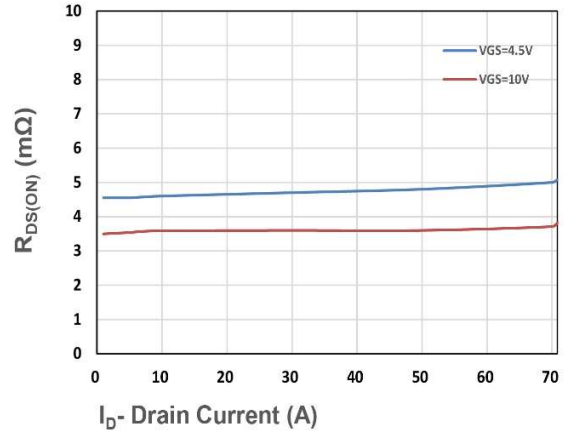


Figure 2. On-Resistance vs. ID

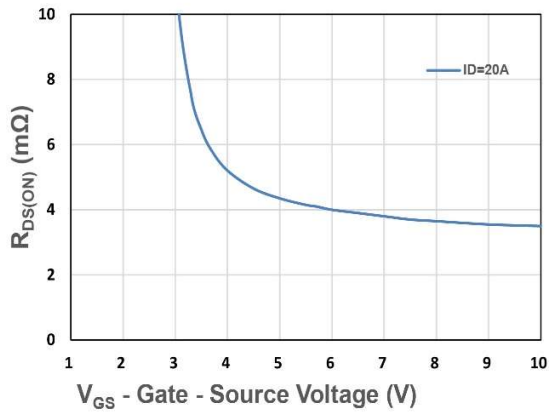


Figure 3. On-Resistance vs. VGS

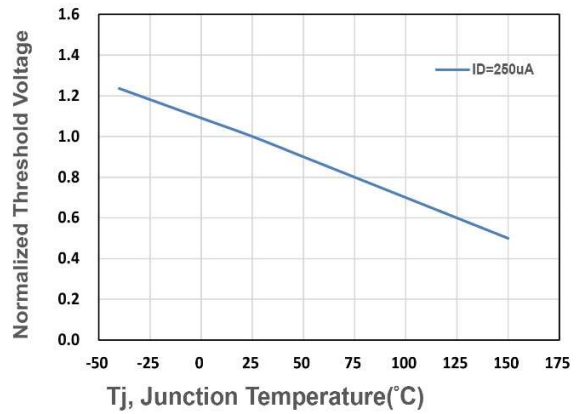


Figure 4. Gate Threshold Voltage

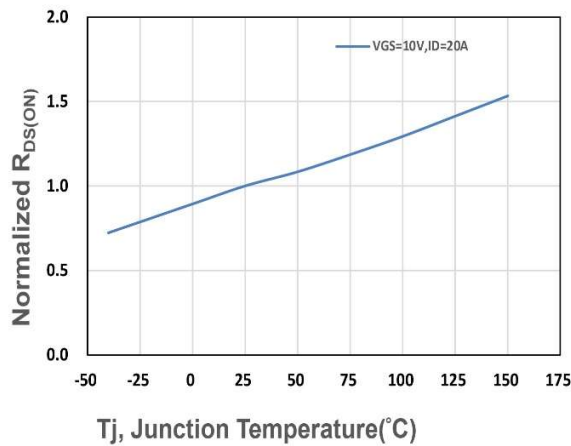


Figure 5. Drain-Source On Resistance

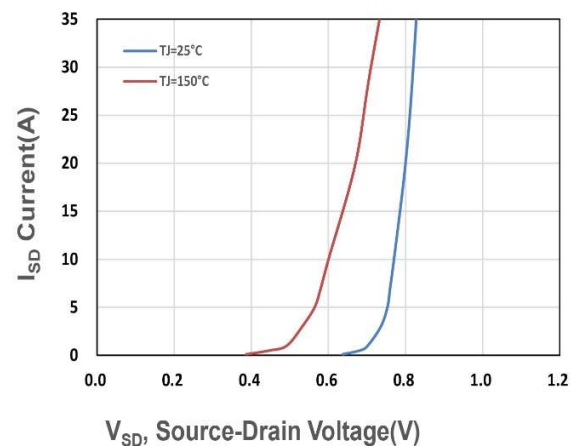


Figure 6. Source-Drain Diode Forward

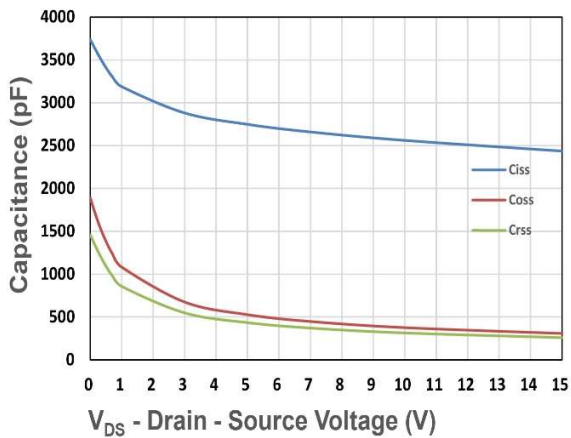


Figure 7. Capacitance

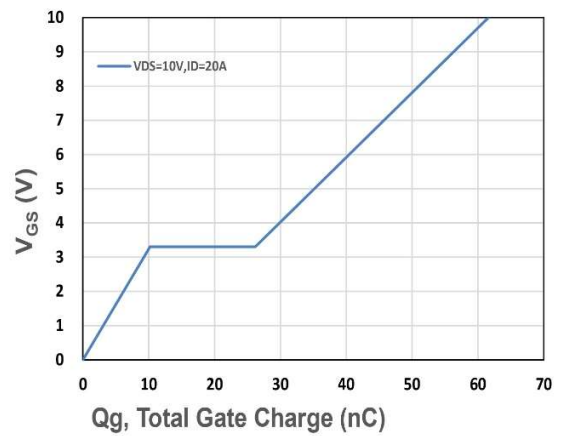


Figure 8. Gate Charge Characteristics

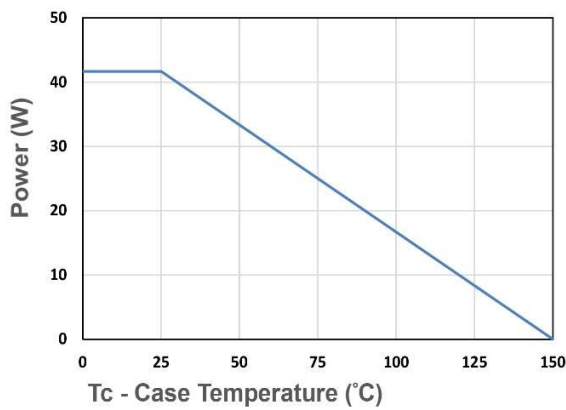


Figure 9. Power Dissipation

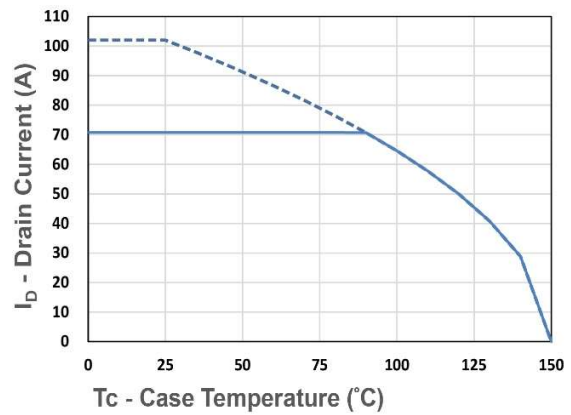


Figure 10. Drain Current

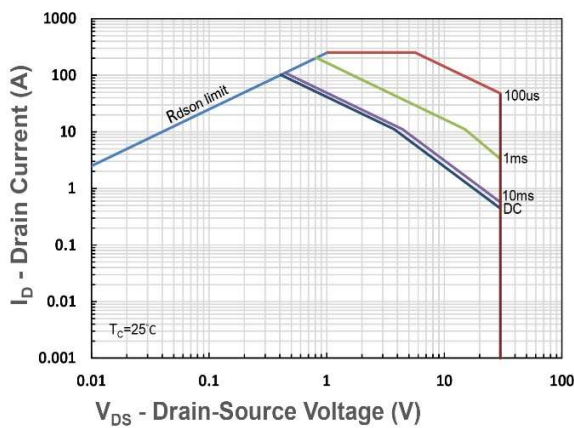


Figure 11. Safe Operating Area

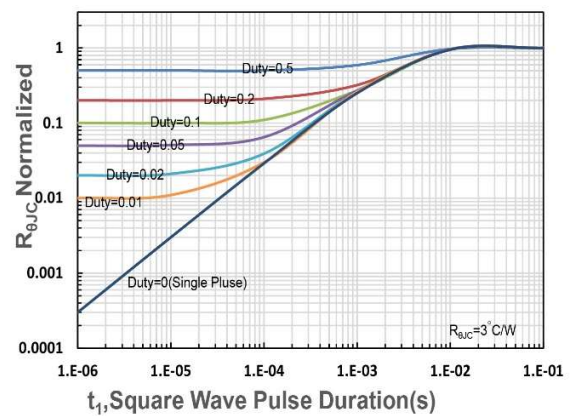


Figure 12. $R_{\theta JC}$ Transient Thermal Impedance